## Application/Control No. Applicant(s)/Patent Under Reexamination 10/659,744 NABEYAMA ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Dzung D. Tran 🕚 2613 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY US-2005/0047786 03-2005 Kawahata, Yuichi 398/081 Α 398/147 В US-2006/0140637 06-2006 Sakata et al. С US-US-D US-Ε US-F US-G US-Н US-US-US-K US-US-FOREIGN PATENT DOCUMENTS **Document Number** Date Name Classification Country Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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